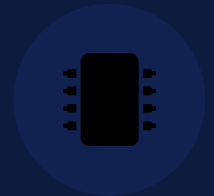


TKS - ATE TESTING - ULTRAFLEX TEST PROGRAM DEVELOPMENT

# Teradyne UltraFLEX Test Program Development (TPD) service



# What is ATE testing?

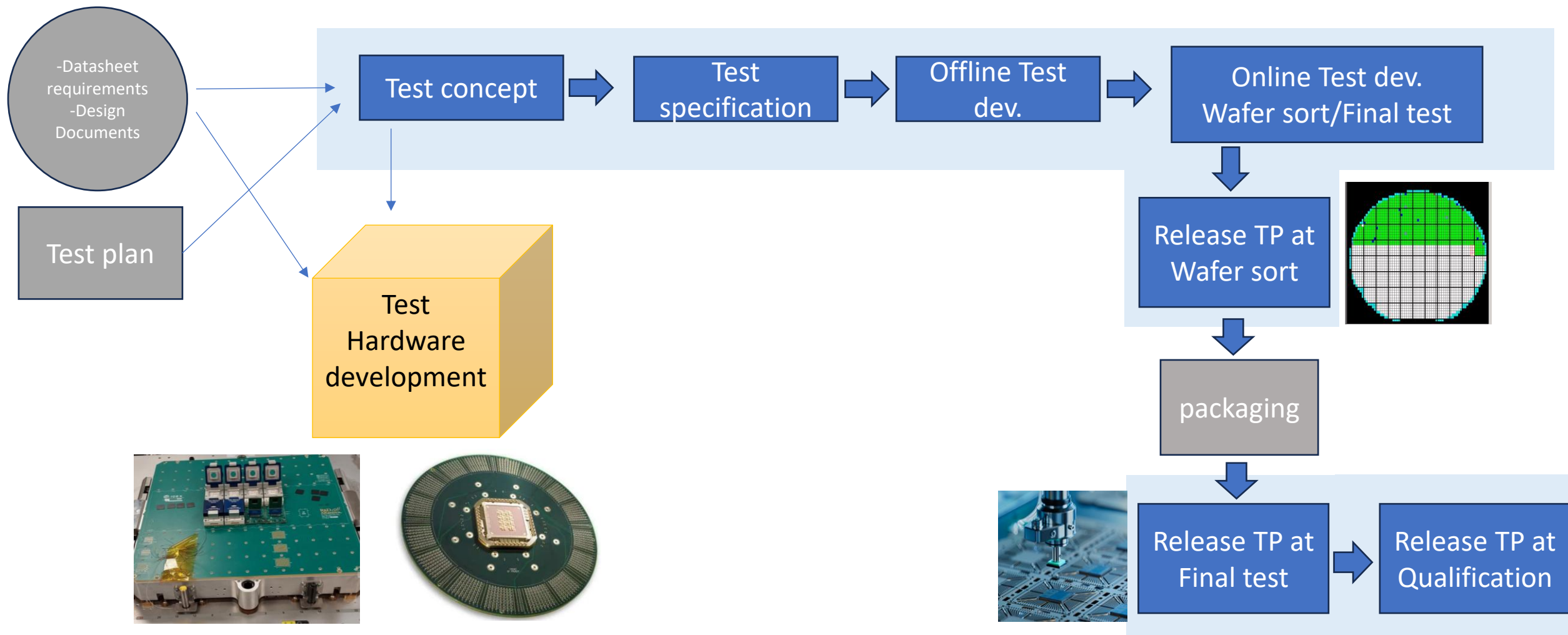
Automated Test equipment (ATE) testing refers to the electrical testing of devices (IC) using a tester platform to screen out defects due to manufacturing steps. ATE testing is done in the shortest amount of time with highest % of yield.

Our team at TKS specializes Test program development in a specific Tester platform - **Teradyne UltraFLEX** for complex digital, radar, wireless, and mixed signal SoC devices, which takes deep tester-specific expertise, and internal teams are often stretched thin across projects.



# Which activities TKS performs in Production Test development cycle?

TKS activity



## WHAT WE DELIVER

# UltraFLEX TPD, Start to Finish

Dedicated Teradyne UltraFLEX test program development for radar MMIC, wireless SoC, and mixed signal devices, covering the full path from test plan to production release.

- ✓ Test plan development and architecture
- ✓ Silicon bringup and characterization on UltraFLEX
- ✓ Debug, correlation, and production release support
- ✓ On-site commissioning and release at your OSAT for small volume or high volume testing



## Device Coverage

Radar MMIC

Wireless SoC

Mixed Signal

UltraFLEX

## One Tester, One Team

UltraFLEX is all we do. That focus means faster ramp on your programs and no context switching across platforms.

# Technical Capabilities

## Test spec examples

- Continuity test (Force Currents measure voltage of ESD structures)
- Leakage test (Force Voltage and measure leakage currents)
- Reference Voltage, currents trimming and measurement (for example bandgap and pstat blocks)
- Digital temp sensor trimming and measurement. (Using a reference diode temp, trim the coefficients at hot and cold)
- Supply monitors trimming and measurement.
- PLL BIST test
- Current Power consumption in radar Application scenario with firmware commands
- DC resistance measurement
- ADC BIST and Gain/Offset measurement
- Contact resistance CRES test for supply lines
- AC impedance test
- SPI and JTAG protocol implementation

## Instruments capability

- Ultrapin1600: DSSC source and capture, PPMU, Digital
- UVI80: DCVI and DC Diff meter
- Ultrapac80: ultrapac src and cap
- Pattern development
- HRAM

## Additional Activities

- IGXL Spike Checker tool
- Gr and R , Binflips correlation analysis
- DOE Test runs and data analysis for characterization IC blocks over splits and temperatures.
- Test time optimization.

WHY WE ARE BETTER

# Competitive advantage

Teams based in Saudi Arabia, Europe and India, that travel on-site for commissioning and release, with remote test development support for the rest of the program lifecycle.



## Importance to quality of test

- Even though we have strong command over technical capabilities of the Ultraflex, we are your partners and take special consideration to understand your device.
- Each test implementation is undergone a rigorous peer reviewed process, so that we ensure no bugs or weak tests are introduced that could lead to test escapes.



## Dedicated Focus

UltraFlex is our only platform, so every engagement benefits from deep, undivided tester expertise in UltraFlex with expertise of members spanning up to 13 years.



## Cost Efficiency

Our optimized global delivery model leverages talent across geographies to provide top-tier expertise at highly competitive rates. You get the quality and focus of a premium provider with the efficiency of a flexible cost structure.

## NEXT STEPS

# Let's Scope a Program

We'd like to walk the your team through our UltraFLEX TPD experience and identify one active or upcoming test program as a starting point.

- 1 Review your current UltraFLEX TPD workload
- 2 Identify a candidate test program
- 3 Scope engagement and timeline

